RD 50 Common Project

Note that the methods developed are rather generic, applicable to a wide variety of the Si devices.

The initial trials started within the framework of ATLAS Planar Pixel Collaboration.

Last summer, the scribe-andcleave technology of fabricating slim edge sensors has also been approved as RD50 project.

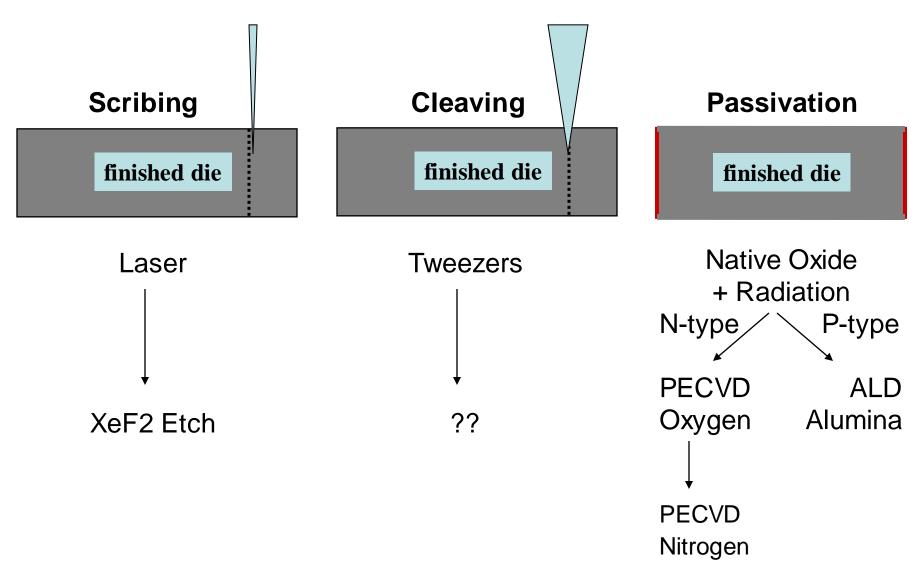
The participating institutions are interested in both p- and n-type sensors.

- Date: 05-26-2011 (Distributed version)	
Title of project:	Development of "slim edges" using cleaving and ALD processing methods
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RD50 funding request

Outside Institutes:1. US Naval Research Laboratory, Bernard Phlips2. FBK Trento, M. Boscardin

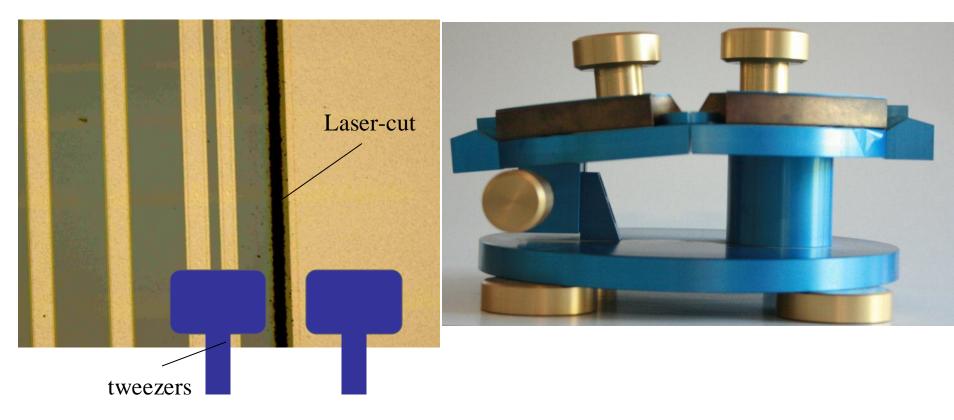
Evolution of Slim Edge Treatment



Different Ways of Cleaving

Optical micrograph, top-view

Wafer Brech Maschine Courtesy PSI and Uni Bonn



R&D for Large-Scale Application

One of the key issues in making further progress is replacement of tweezer-based cleaving with better methods.

If somebody has a better machine, that could be shared or loaned, we are interested! Looking at the industrial-scale cleaving machines:

- Dynatex machines seem nice. However we have a major delay in scheduling a test run with them.
- Loomis seem to be less automated, but suitable. Have started on a test run soon.



ATED BREAKER PRODUCTION SYSTEM

GaAs wafer, diced and expanded. Wafe<mark>r dicing is well-</mark> suited for UV DPSS lasers with their highly focusable, pinpoint-bright beams

Dynatex International DTX-20

LOOMIS Industries LSD-150



Redirection of Funds in Support of Cleaving

- Budget:
 - CHfr 32k for treatment at NRL
 - CHfr 16k for sensors

We feel we have sufficient large n-type sensors But no experience with large p-type sensors Propose to acquire a few wafers from the new RD50 run ("Low R") at CNM for this (~ CHfr 3k) Possibility to acquire SMART sensors from FBK.

• Redirection:

Would like to spend < CHfr 10k on contract work with industry (Loomis Industries), and constructing a "Waferbrechmaschine" (courtesy of PSI and Uni Bonn) in the UCSC University shop.

The participating institutions have either agreed or have not voiced objection.